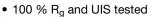
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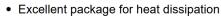
# N- and P-Channel 30 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY							
	V <sub>DS</sub> (V)	$R_{DS(on)}$ (m $\Omega$ )(Typ.)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
N-Channel	30	6.5 at $V_{GS} = 10 \text{ V}$	40	15			
		$9.8  \text{at V}_{GS} = 4.5  \text{V}$	40	13			
P-Channel	- 30	10 at V <sub>GS</sub> = - 10 V	- 40	30			
r - Onamie	- 30	16 at V <sub>GS</sub> = - 4.5 V	1 - 40	30			

#### **FEATURES**

• DT-SJ Power MOSFET

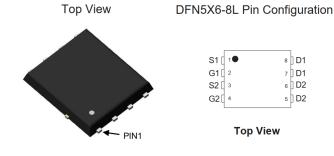


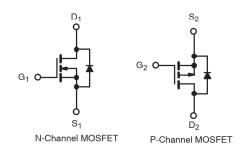


• Halogen Free

## **APPLICATIONS**

- · Load switching
- Hard switched and high frequency circuits





ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	N-Channel	P-Channel	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	30	- 30	· ·		
Gate-Source Voltage	V <sub>GS</sub>	± 20	± 20	V		
Continuous Drain Current (T <sub>.I</sub> = 150 °C) <sup>a</sup>	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	40	- 40	A	
Continuous Drain Current (1) = 150 C)	T <sub>C</sub> = 100 °C		27	- 27		
Pulsed Drain Current <sup>b</sup>		I <sub>DM</sub>	120	- 140		
Maximum Power Dissipation <sup>c</sup>	T <sub>C</sub> = 25 °C	В	48	50	w	
Maximum Fower Dissipation-	T <sub>C</sub> = 100 °C	- P <sub>D</sub>	19	20	VV	
Single Avalanche Energy	E <sub>AS</sub>	55	85	mJ		
Operating Junction and Storage Temperature Rang	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150		°C		

THERMAL RESISTANCE RATINGS							
		N-Channel	P-Channel				
Parameter		Symbol	Limit	Limit	Unit		
Maximum Junction-to-Ambient <sup>d</sup> t ≤ 10 s		R <sub>thJA</sub>	50	50	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	2.6	2.5	C/ <b>VV</b>		

#### Notes

- a. Calculated continuous current based on maximum allowablejunction temperature.
- b. Repetitive rating; pulse width limited by max. junction temperature.
- c. Pd is based on max. junction temperature, using junction-case thermal resistance.
- d. The value of R<sub>0,JA</sub> is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper,in a still air environment with Ta=25 °C.



PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30	-	-	V	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0	-	2.5	ľ	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	1 10		1	μА	
Zero Gate Voltage Drain Gunerit		V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 5 \text{ V}$	40	-	-	Α	
Drain-Source On-State Resistance a	P	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A	-	6.5	8.5	mO	
Diani-Source On-State Nesistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 10 A	-	9.8	15	mΩ	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 15 A	-	53	-	S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>		-	898	-	pF	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15 V, f = 1 MHz	-	153	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	89	-		
Total Gate Charge <sup>c</sup>	Qg		-	15	-		
Gate-Source Charge <sup>c</sup>	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$	-	1.8	-	nC	
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$		-	2.5	-		
Gate Resistance	$R_g$	f = 1 MHz	-	13	-	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>		-	8	-		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A}, R_{g} = 2.5 \Omega$	-	18	-	- ns	
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	V <sub>GS</sub> = 10 V	-	22	-		
Fall Time <sup>c</sup>	t <sub>f</sub>		-	23	-		
<b>Drain-Source Body Diode Ratings and</b>	Characterist	ics <sup>b</sup> (T <sub>C</sub> = 25 °C)					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	-	-	40	Α	
Pulsed Current (t = 100 µs)	I <sub>SM</sub>		-	-	120	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 1 A, V <sub>GS</sub> = 0 V	-	-	1.2	V	
Reverse Recovery Time	t <sub>rr</sub>	1 15 A di/dt 100 A/:	-	6	-	ns	
Reverse Recovery Charge	Q <sub>rr</sub>	$I_F = 15 \text{ A, di/dt} = 100 \text{ A/µs}$		0.3	-	nC	

#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



P-Channel Electrical Characteristics (T <sub>J</sub> = 25 °C, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT		
Static								
Drain-Source Breakdown Voltage	$V_{DS}$ $V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		- 30	-	-	V		
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0	-	- 2.5			
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA		
Zero Gate Voltage Drain Current	1	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	1 10		- 1	μА		
Zero date voltage Brain Gunent	I <sub>DSS</sub>	V <sub>DS</sub> = - 24 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10			
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -5$ , $V_{GS} = -5$ V	- 40	-	-	Α		
Drain-Source On-State Resistance a	Boo.	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 15 A	-	10	13			
Diani-Source On-State Nesistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10 A	-	16	22	mΩ		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 5 V, I <sub>D</sub> = - 15 A	-	60	-	S		
Dynamic <sup>b</sup>								
Input Capacitance	C <sub>iss</sub>		-	2310	-	pF		
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = - 15 V, f = 1 MHz	-	250	-			
Reverse Transfer Capacitance	C <sub>rss</sub>		-	255	-			
Total Gate Charge <sup>c</sup>	$Q_g$		-	30	-	nC		
Gate-Source Charge <sup>c</sup>	$Q_{gs}$	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -15 \text{ A}$	-	4	-			
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>		-	1	-			
Gate Resistance	$R_g$	f = 1 MHz	-	6.5	-	Ω		
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>		-	7.5	-			
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DS} = -15 \text{ V}, I_{D} = -15 \text{ A}, R_{g} = 2.5 \Omega$	-	5	-	- ns		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	V <sub>GS</sub> = - 10 V	-	105	-			
Fall Time <sup>c</sup>	t <sub>f</sub>		-	70	-			
<b>Drain-Source Body Diode Ratings and</b>	Characterist	tics <sup>b</sup> (T <sub>C</sub> = 25 °C)						
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C	-	-	- 40	Α		
Pulsed Current (t = 100 µs)	I <sub>SM</sub>		-	-	- 140	Α		
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = - 1 A, V <sub>GS</sub> = 0 V	-	-	- 1.2	٧		
Reverse Recovery Time	t <sub>rr</sub>	1 45 A 31/31 400 A/3	-	18	-	ns		
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 15 A, di/dt = 100 A/μs	_	39	_	nC		

#### Notes

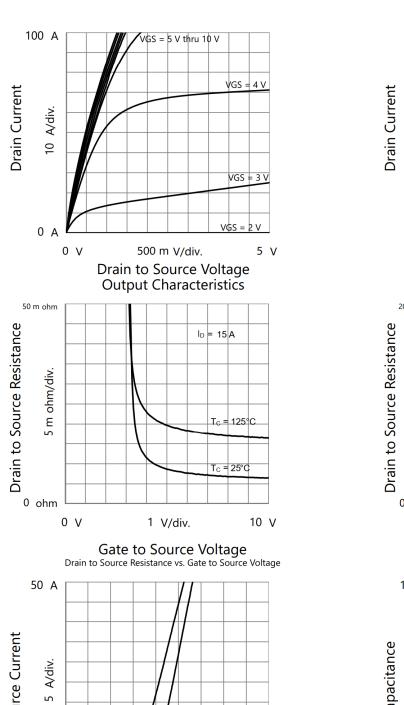
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

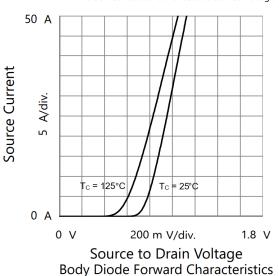
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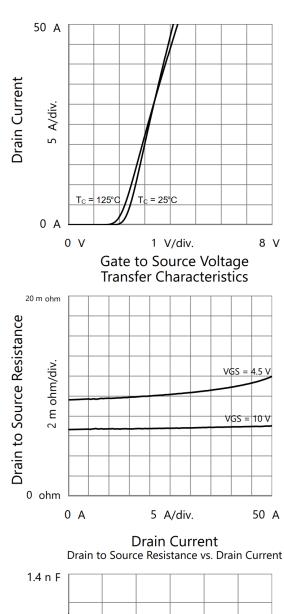
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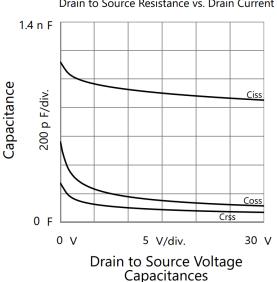
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## N-CHANNEL TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



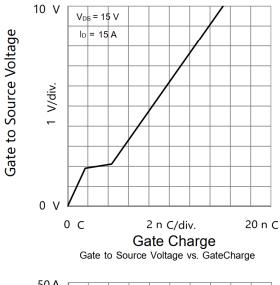


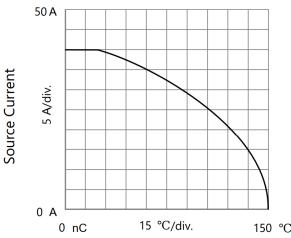


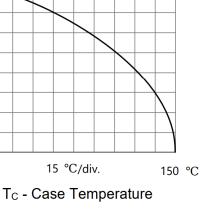


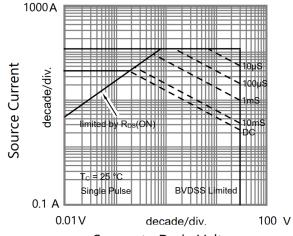


## N-CHANNEL TYPICAL CHARACTERISTICS (25°C, unless otherwise noted)

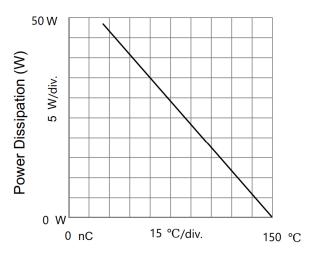




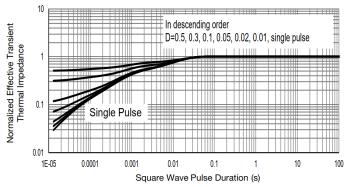




Source to Drain Voltage Safe Operating Area, Junction-to-Ambient

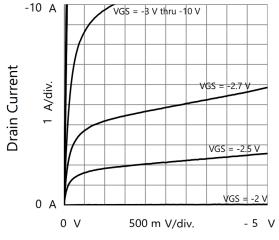


T<sub>C</sub> - Case Temperature

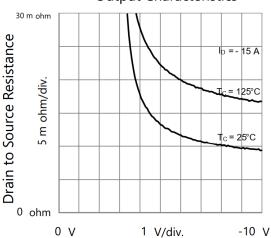


Normalized Thermal Transient Impedance, Junction-to-Case

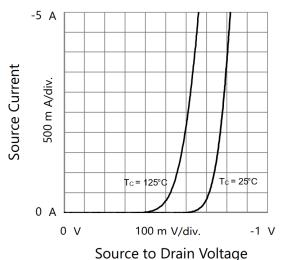
## P-CHANNEL TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



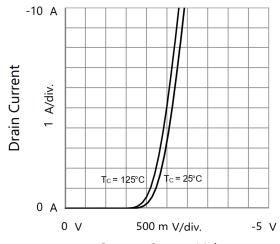
Drain to Source Voltage Output Characteristics



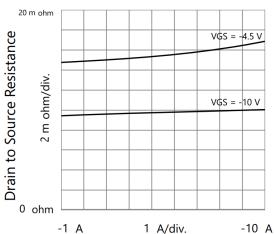
Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage



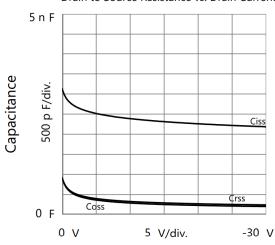
**Body Diode Forward Characteristics** 



Gate to Source Voltage Transfer Characteristics

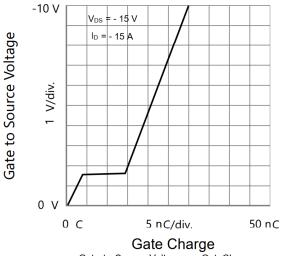


Drain Current
Drain to Source Resistance vs. Drain Current



Drain to Source Voltage Capacitances

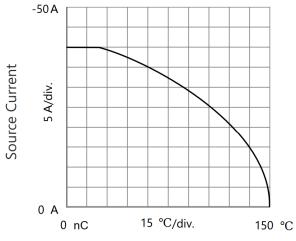
## P-CHANNEL TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



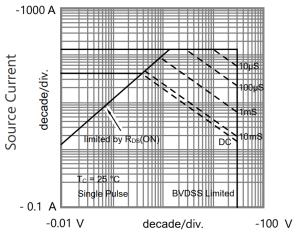
**Din-Tek** 

**SEMICONDUCTOR** 

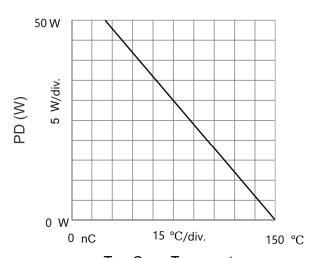




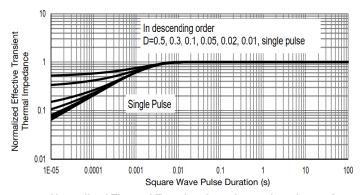
 $T_{C} \textbf{-} \textbf{Case Temperature}_{\text{Current Derating}}$ 



Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



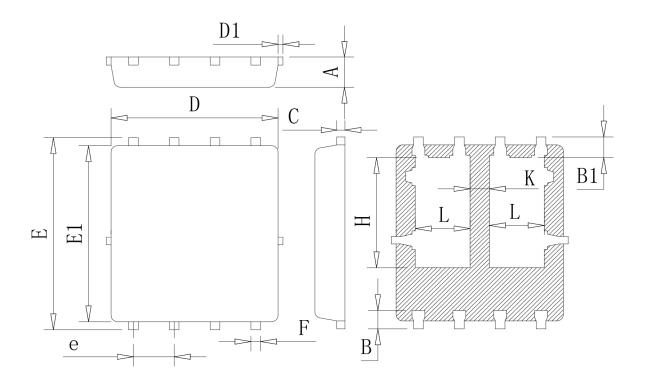
 $T_{C} \textbf{-} \textbf{Case Temperature}_{Power \ Derating}$ 



Normalized Thermal Transient Impedance, Junction-to-Case



# **DFN5X6-8L-D PACKAGE OUTLINE**



# **COMMON DIMENSIONS** (UNITS OF MEASURE=MILLIMETER)

Symbol	Min	Тур	Max
A	0.85	0.95	1.05
В	0.46	0.58	0.73
B1	0.52	0.65	0.78
С	0.18	0.254	0.32
D	4.70	5.20	5.50
D1	-	-	0.18
Е	5.75	6.05	6.35
E1	5.35	5.65	5.85
e	1.15	1.27	1.50
F	0.15	0.30	0.50
Н	3.15	3.47	3.80
L	1.35	1.70	2.10
K	0.35	0.60	1.00





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